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(54) SUPPLEMENTAL TECHNIQUES FOR CHARACTERIZING POWER QUALITY EVENTS IN AN ELECTRICAL SYSTEM

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ABSTRACT (57)

A method for characterizing power quality events in an electrical system includes deriving electrical measurement data for at least one first virtual meter in an electrical system from (a) electrical measurement data from or derived from energy-related signals captured by at least one first IED in the electrical system, and (b) electrical measurement data from or derived from energy-related signals captured by at least one second IED in the electrical system. In embodiments, the at least one first IED is installed at a first metering point in the electrical system, the at least one second IED is installed at a second metering point in the electrical system, and the at least one first virtual meter is derived or located at a third metering point in the electrical system. The derived electrical measurement data may be used to generate or update a dynamic tolerance curve associated with the third metering point.

